## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | KIM ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,782,858	11-1988	Fujiwara, Takayoshi	417/312
*	В	US-5,173,034	12-1992	Riffe, Delmer R.	181/403
*	С	US-5,304,044	04-1994	Wada et al.	417/312
*	D	US-5,328,338	07-1994	Hirano et al.	417/312
*	E	US-5,542,824	08-1996	Lee, Sung-Tae	417/312
*	F	US-5,641,949	06-1997	Yeo, Kerk Kan	181/229
*	G	US-5,769,613	06-1998	Kim, Ki-Back	181/229
*	Н	US-6,572,345	06-2003	Seo, Seung-don	417/312
*	1	US-6,641,374	11-2003	Kim, Jong Hyuk	417/312
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	v		
	w		
	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.